To all our customers

# Regarding the change of names mentioned in the document, such as Mitsubishi Electric and Mitsubishi XX, to Renesas Technology Corp.

The semiconductor operations of Hitachi and Mitsubishi Electric were transferred to Renesas Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.) Accordingly, although Mitsubishi Electric, Mitsubishi Electric Corporation, Mitsubishi Semiconductors, and other Mitsubishi brand names are mentioned in the document, these names have in fact all been changed to Renesas Technology Corp. Thank you for your understanding. Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been made to the contents of the document, and these changes do not constitute any alteration to the contents of the document itself.

Note : Mitsubishi Electric will continue the business operations of high frequency & optical devices and power devices.

Renesas Technology Corp. Customer Support Dept. April 1, 2003



#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

#### DESCRIPTION

The M5M5W816TP is a family of low voltage 8-Mbit static RAMs organized as 524288-words by 16-bit, fabricated by Mitsubishi's high-performance  $0.18\mu m$  CMOS technology.

The M5M5W816TP is suitable for memory applications where a simple interfacing , battery operating and battery backup are the important design objectives.

The M5M5W816TP is packaged in a 44pin thin small outline mount device, with the outline of 400mil TSOP TYPE(II). It gives the best solution for a compaction of mounting area as well as flexibility of wiring pattern of printed circuit boards.

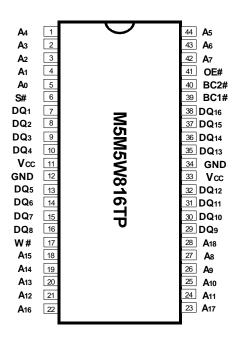
#### FEATURES

- Single 2.7~3.6V power supply
- Small stand-by current: 0.1µA (2.0V, typ.)
- No clocks, No refresh
- Data retention supply voltage =2.0V
- All inputs and outputs are TTL compatible.
- Easy memory expansion by S#, BC1# and BC2#
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE# prevents data contention in the I/O bus
- Process technology: 0.18µm CMOS
- Package: 44pin 400mil TSOP TYPE(II)

Version,		5			S	Stand-b	y curre	ent		Active
Operating	Part name	Power		* Typ. (@	2 3.0V)	Rati	ngs (m	nax. @	3.6V)	current
temperature		Supply	max.	25°C	40°C	25°C	40°C	70°C	85°C	lcc1 *(3.0V typ.)
Lucasian	M5M5W816TP -55HI		55ns							30mA
I-version	M5M5W816TP -70HI	2.7~3.6V	70ns	0.5	1.0	5.0	8.0	20	40	(10MHz) 5mA
-40~+85°C	M5M5W816TP -85HI		85ns							(1MHz)

\* Typical parameter indicates the value for the center of distribution, and not 100% tested.

#### **PIN CONFIGURATION**



44Pin 400mil TSOP Outline: 44P3W

Pin	Function
A0 ~ A18	Address input
DQ1 ~ DQ16	Data input / output
S#	Chip select input
W#	Write control input
OE#	Output enable input
BC1#	Lower Byte (DQ1 ~ 8)
BC2#	Upper Byte (DQ9~16)
Vcc	Power supply
GND	Ground supply

Renesas Technology Corp.

#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

#### FUNCTION

The M5M5W816TP is organized as 524288-words by 16bit. These devices operate on a single +2.7~3.6V power supply, and are directly TTL compatible to both input and output. Its fully static circuit needs no clocks and no refresh, and makes it useful.

The operation mode are determined by a combination of the device control inputs BC1# , BC2# , S# , W# and OE#. Each mode is summarized in the function table.

A write operation is executed whenever the low level W# overlaps with the low level BC1# and/or BC2# and the low level S#. The address(A0~A18) must be set up before the write cycle and must be stable during the entire cycle.

A read operation is executed by setting W# at a high level and OE# at a low level while BC1# and/or BC2# and S# are in an active state(S#=L).

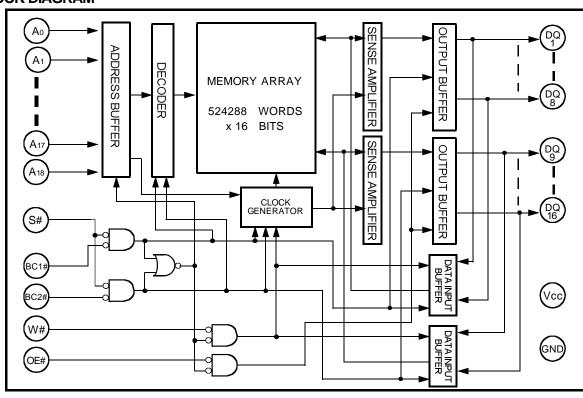
When setting BC1# at the high level and other pins are in an active stage, upper-byte are in a selectable mode in which both reading and writing are enabled, and lower-byte are in a non-selectable mode. And when setting BC2# at a high level and other pins are in an active stage, lowerbyte are in a selectable mode and upper-byte are in a non-selectable mode. When setting BC1# and BC2# at a high level or S# at a high level, the chips are in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips and memory expansion by BC1#, BC2# and S#.

The power supply current is reduced as low as  $0.1\mu A(25^{\circ}C, ty pical)$ , and the memory data can be held at +2.0V power supply, enabling battery back-up operation during power failure or power-down operation in the non-selected mode.

#### **FUNCTION TABLE**

S#	BC1#	BC2#	W#	OE#	Mode	DQ1~8	DQ9~16	lcc
Н	Х	Х	Х	Х	Non selection	High-Z	High-Z	Standby
Х	Н	Н	Х	Х	Non selection	High-Z	High-Z	Standby
L	L	Н	L	Х	Write	Din	High-Z	Active
L	L	Н	Н	L	Read	Dout	High-Z	Active
L	L	Н	Н	Н		High-Z	High-Z	Active
L	Н	L	L	Х	Write	High-Z	Din	Active
L	Н	L	Н	L	Read	High-Z	Dout	Active
L	Н	L	Н	Н		High-Z	High-Z	Active
L	L	L	L	Х	Write	Din	Din	Activ e
L	L	L	Н	L	Read	Dout	Dout	Active
L	L	L	Н	Н		High-Z	High-Z	Active

(note) "H" and "L" in this table mean VIH or VIL, respectively. "X" in this table should be "H"or "L".





#### **BLOCK DIAGRAM**

#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

#### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Units
Vcc	Supply voltage	With respect to GND	-0.3* ~ +4.6	
Vi	Input voltage	With respect to GND	-0.3* ~ Vcc + 0.3 (max. 4.6V)	V
Vo	Output voltage	With respect to GND	0 ~ Vcc	
Pd	Power dissipation	Ta= 25°C	700	mW
Ta	Operating temperature		- 40 ~ +85	°C
T stg	Storage temperature		- 65 ~ +150	°C

\* -3.0V in case of AC (Pulse width  $\leq$  30ns)

### DC ELECTRICAL CHARACTERISTICS

(Vcc=2.7 ~ 3.6V, unless otherwise noted)

					Limits	;	
Symbol	Parameter	Conditions		Min	Тур	Max	Units
Vін	High-lev el input voltage			2.2		Vcc+0.2V	
VIL	Low-lev el input voltage			-0.2 *		0.6	
Vон	High-level output voltage	Іон <b>= - 0.5mA</b>		2.4			V
Vol	Low-level output voltage	Iol=2mA				0.4	
h	Input leakage current	Vi=0 ~ Vcc				±1	μA
lo	Output leakage current	BC1# and BC2#=VIH or S#=VIH or OE#=VIH, VI/O=0	~ Vcc			±1	μΛ
Icc1	Active supply current	BC1# and BC2# $\leq$ 0.2V, S# $\leq$ 0.2V other inputs $\leq$ 0.2V or $\geq$ Vcc-0.2V	f= 10MHz	-	30	50	
ICCT	(AC,MOS level)	Output - open (duty 100%)	f= 1MHz	-	5	15	
	Active supply current	BC1# and BC2#=VIL,S#=VIL other pins =VIH or VIL	f= 10MHz	-	30	50	mA
lcc2	(AC,TTL level)	Output - open (duty 100%)	f= 1MHz	-	5	15	
		(1) S# ≥ Vcc - 0.2V,	~ +25°C	-	0.5	5	
	Stand by supply current	other inputs = 0 ~ Vcc	~ +40°C	-	1.0	8	
Icc3	( AC,MOS level )	(2) BC1# and BC2# $\geq$ Vcc - 0.2V	~ +70°C	-	-	20	μA
		$S\# \le 0.2V$ other inputs = 0 ~ Vcc	~ +85°C	-	-	40	
lcc4	Stand by supply current (AC,TTL level)	BC1# and BC2# = VIH or S# = VIH Other inputs= 0 ~ Vcc		-	-	2	mA

Note 1: Direction for current flowing into IC is indicated as positive (no mark).

\* -1.0V in case of AC (Pulse width  $\leq$  30ns)

Note 2: Typical parameter indicates the value for the center of distribution at 3.0V, and not 100% tested.

### CAPACITANCE

(Vcc=2.7 ~ 3.6V, unless otherwise noted)

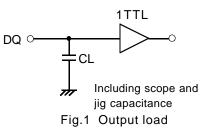
Symbol	Parameter	Conditions		Limits			
Cymbol	Falameter	Conditions	Min	Тур	Max	Units	
Cı	Input capacitance	VI=GND, VI=25mVrms, f=1MHz			10	pF	
Co	Output capacitance	Vo=GND,Vo=25mVrms, f=1MHz			10	рі	



#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

#### AC ELECTRICAL CHARACTERISTICS (Vcc=2.7 ~ 3.6V, unless otherwise noted) (1) TEST CONDITIONS

) TEST CONDITIONS	
Supply voltage	2.7~3.6V
Input pulse	VIH=2.4V, VIL=0.4V
Input rise time and fall time	5ns
Reference level	VoH=VoL=1.50V Transition is measured ±200mV from steady state voltage.(for ten,tdis)
Output loads	Fig.1,CL=30pF CL=5pF (for ten.tdis)



### (2) READ CYCLE

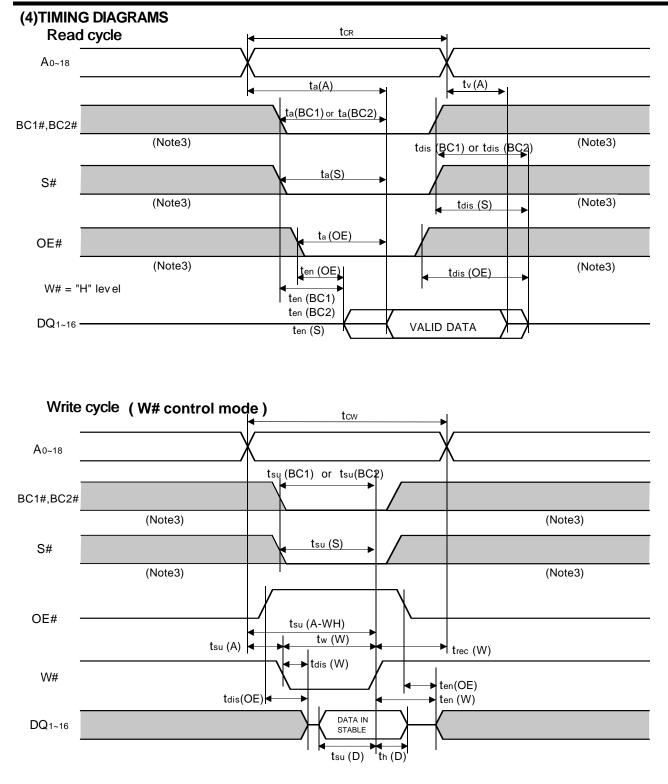
		Limits						
Symbol	Parameter	55HI		70HI		85HI		Units
Cymbol		Min	Max	Min	Max	Min	Max	
tcr	Read cycle time	55		70		85		ns
ta(A)	Address access time		55		70		85	ns
ta(S)	Chip select 1 access time		55		70		85	ns
ta(BC1)	Byte control 1 access time		55		70		85	ns
ta(BC2)	Byte control 2 access time		55		70		85	ns
ta(OE)	Output enable access time		30		35		45	ns
tdis(S)	Output disable time after S# high		20		25		30	ns
tdis(BC1)	Output disable time after BC1# high		20		25		30	ns
tdis(BC2)	Output disable time after BC2# high		20		25		30	ns
tdis(OE)	Output disable time after OE# high		20		25		30	ns
ten(S)	Output enable time after S# low	10		10		10		ns
ten(BC1,2)	Output enable time after BC1#,BC2# low	5		5		5		ns
ten(OE)	Output enable time after OE# low	5		5		5		ns
t∨(A)	Data valid time after address	10		10		10		ns

### (3) WRITE CYCLE

		Lin						
Symbol	Parameter	55	55HI		70HI		85HI	
,		Min	Max	Min	Max	Min	Max	
tcw	Write cycle time	55		70		85		ns
t <sub>w</sub> (W)	Write pulse width	45		55		60		ns
tsu(A)	Address setup time	0		0		0		ns
t <sub>su</sub> (A-WH)	Address setup time with respect to W#	50		65		70		ns
tsu(BC1)	Byte control 1 setup time	50		65		70		ns
tsu(BC2)	Byte control 2 setup time	50		65		70		ns
tsu(S)	Chip select setup time	50		65		70		ns
tsu(D)	Data setup time	30		35		45		ns
th(D)	Data hold time	0		0		0		ns
trec(W)	Write recovery time	0		0		0		ns
tdis(W)	Output disable time from W# low		20		25		30	ns
tdis(OE)	Output disable time from OE# high		20		25		30	ns
ten(W)	Output enable time from W# high	5		5		5		ns
ten(OE)	Output enable time from OE# low	5		5		5		ns

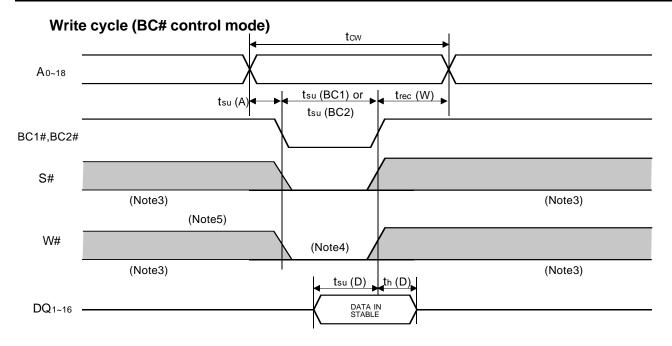


#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM





### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM



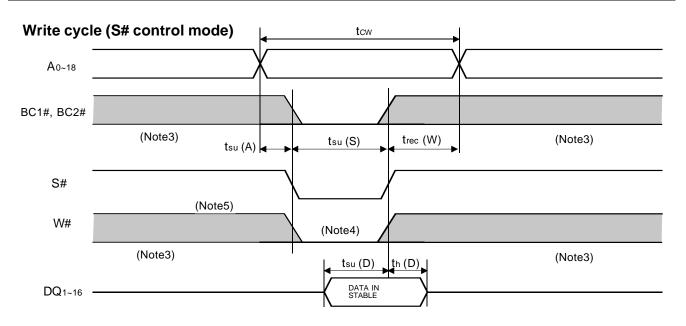
Note 3: Hatching indicates the state is "don't care".

Note 4: A Write occurs during S# low ov erlaps BC1# and/or BC2# low and W# low.

- Note 5: When the falling edge of W# is simultaneously or prior to the falling edge of BC1# and/or BC2# or the falling edge of S#, the outputs are maintained in the high impedance state.
- Note 6: Don't apply inverted phase signal externally when DQ pin is in output mode.



#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM





8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

### **POWER DOWN CHARACTERISTICS** (1) ELECTRICAL CHARACTERISTICS

	5							
Symbol	Parameter	Test conditions	Min	Тур	Max	Units		
Vcc (PD)	Power down supply voltage			2.0			V	
VI (BC)	Byte control input BC1# & BC2#	$2.2V \leq Vcc(PD)$		2.2			V	
()	• • • • • • • • • • • • • • • • •	2.0V <u>≤</u> Vcc(PD) <u>≤</u> 2.2V		Vcc(PD)		v		
ML (D)	Ohin as last innut Oll	2.2V <u>&lt;</u> Vcc(PD)		2.2			N/	
VI (S)	Chip select input S#	2.0V <u>&lt;</u> Vcc(PD) <u>&lt;</u> 2.2V			Vcc(PD)		V	
		Vcc=2.0V	~ +25°C	-	0.1	1.5		
Icc (PD)	Power down	(1) S# $\geq$ Vcc - 0.2V, other inputs = 0 ~ Vcc	~ +40°C	-	0.2	3		
supply current	(2) BC1# and BC2# ≥ Vcc - 0.2V	~ +70°C	-	-	15	μA		
		$S\# \leq 0.2V$ other inputs = 0 ~ Vcc	~ +85°C	-	-	30		

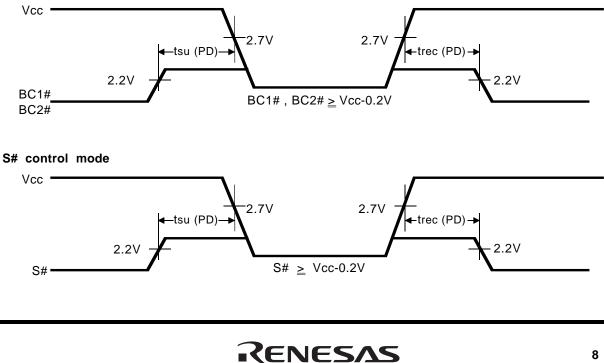
Note 7: Typical parameter of Icc(PD) indicates the value for the center of distribution at 2.0V, and not 100% tested.

#### (2) TIMING REQUIREMENTS

				Linite		
Symbol	Parameter	Test conditions	Min	Тур	Max	Units
tsu (PD)	Power down set up time		0			ns
trec (PD)	Power down recovery time		5			ms

### (3) TIMING DIAGRAM

BC# control mode On the BC# control mode, the level of S# must be fixed at S#  $\geq$  Vcc-0.2V or S#  $\leq$  0.2V.



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